SIEMENS

Microcomputer Components
Technical Support Group Munich
HL MCB MC PD 2

Errata Sheet

March 21, 1994 / Release 1.2

Device : SAB 80C515 / 80C535

Marking : DA

These parts of the SAB 80C515 / 80C535 can be identified by the letters "DA" below the part number. The parts are mounted in a plastic leaded chip carrier package (P-LCC-68).

This errata sheet describes both the *functional problems* (see part 1) and the *deviations from the electrical and timing specifications* (see part 2) known in this step.

If a problem was already introduced with an errata sheet of an earlier step, its initial number is still retained in this errata sheet. Thus, the numerical order of the problems described in the following may contain gaps.

At the end of this document, you will find two history tables showing the problems found in the SAB 80C515A up to now. Changes to the last revision are shaded light grey in the history tables.

1) Functional Problems

The following malfunctions are known in this step:

No functional problems known.

2) Electrical- and Timing-Spec. Deviations

The following deviations of electrical and timing parameters from the specification are known in this step:

Deviation 2: V_{IL1} and V_{IH} for EA# pin

The input low voltage and the input high voltage for the EA# pin are changed as follows:

Parameter	Symbol	Limit Values		Unit	Test Condition
		Min.	Max.		
Input Low Voltage (EA')	V_{IL1}	-0,5	**$0.1V_{CC}$**	V	---
Input High Voltage	V_{IH}	**$0.6V_{CC}$**	V_{CC}+0.5	V	---

Changed values are written in bold letters.

Deviation 5: A/D Converter, Internal Reference Error, $V_{INTREFERR}$

The maximum limit value of the internal reference error $V_{INTREFERRmax} = \pm$ 30mV is not met.

For this step $V_{INTREFERR}$ is defined to $V_{INTREFERRmax} = \pm$50mV.

Deviation 6: A/D Converter - DNLE, INLE, Gain, Offset

The Differential Non-Linearity Error (DNLE), the Integral Non-Linearity Error (INLE), the Gain Error and the Offset Error is no more specified. The measured values of these parameters are used to calculate the Total Unadjusted Error (TUE) but are no pass/fail criterions during the test of the parts. The data sheet will be changed without notice.

Functional Problem No.	Marking	Description	Remarks

Table 1: History of Functional Problems

Electrical- / Timing-Deviation No.	Marking	Description	Remarks
6	BB, CA, CB, DA	ADC - DNLE, INLE, Gain, Offset	
5	BB, CA, CB, DA	ADC - Internal Reference Error	
4	BB, CA, CB, DA	Input Low Current XTAL2, I_{IL3}	data sheet updated
3	BB, CA, CB DA	Logic 0 Input Current, I_{IL}	data sheet updated
2	BB, CA, CB, DA	V_{IL1} and V_{IH} for EA# pin	
1	BB	Power Down Current, I_{PD}	fixed in CA and later

Table 2: History of Electrical- and Timing-Spec. Deviations